

UNISONIC TECHNOLOGIES CO., LTD

18N50 **Preliminary Power MOSFET**

18 Amps, 500 Volts N-CHANNEL POWER MOSFET

DESCRIPTION

The UTC 18N50 is an N-channel enhancement mode Power MOSFET using UTC's advanced planar stripe and DMOS technology to provide perfect performance.

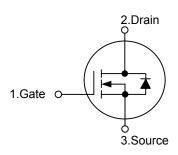
This technology can withstand high energy pulse in the avalanche and commutation mode. It can provide minimum on-state resistance and high switching speed.

This device is generally applied in active power factor correction and high efficient switched mode power supplies.

FEATURES

- * 18A, 500V, $R_{DS(ON)}$ =0.265 Ω @ V_{GS} =10V
- * High switching speed
- * Typically 45nC low gate charge
- * 100% avalanche tested
- * Typically 25pF low C_{RSS}
- * Improved dv/dt capability

SYMBOL

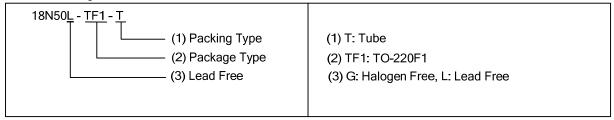


TO-220F1

ORDERING INFORMATION

Ordering Number		Deekees	Pin Assignment			Dealine	
Lead Free	Halogen Free	Package	1	2	3	Packing	
18N50L-TF1-T	18N50G -TF1-T	TO-220F1	G	D	S	Tube	

Note: Pin Assignment: G: Gate D: Drain S: Source



■ ABSOLUTE MAXIMUM RATINGS

PARAMETER		SYMBOL	RATINGS	UNIT	
Drain to Source Voltage		V_{DSS}	500	V	
Gate to Source Voltage		V_{GSS}	±30	V	
Dunin Ourmant		Continuous	I_{D}	18	Α
Drain Current		Pulsed (Note 1)	I_{DM}	72 (Note 6)	Α
Avalanche Energy	Sing	e Pulsed (Note 2)	E _{AS}	945	mJ
	Repetitive (Note 1)		E _{AR}	23.5	mJ
Avalanche Current (Note 1)		I _{AR}	18	Α	
Peak Diode Recovery dv/dt (Note 3)		dv/dt	4.5	V/ns	
Power Dissipation		P_{D}	38.5	W	
Junction Temperature		TJ	+150	°C	
Storage Temperature		T _{STG}	-55 ~ +150	°C	

Note: Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress ratings only and functional device operation is not implied.

■ THERMAL DATA

PARAMETER	SYMBOL	RATINGS	UNIT	
Junction to Ambient	θ_{JA}	62.5	°C/W	
Junction to Case	θ_{Jc}	3.3	°C/W	

■ ELECTRICAL CHARACTERISTICS (T_C=25°C, unless otherwise specified)

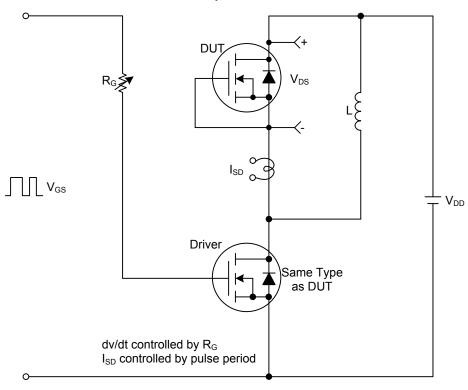
PARAMETER		SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage		BV _{DSS}	V _{GS} =0V, I _D =250μA	500			٧
Breakdown Voltage Temperature Coefficient		$\Delta BV_{DSS}/\Delta T_{J}$	I _D =250μA, Referenced to 25°C		0.5		V/°C
Drain-Source Leakage Current		I _{DSS}	V _{DS} =500V, V _{GS} =0V V _{DS} =400V, T _C =125°C			1 10	μA μA
Gate-Source Leakage Current Fo	rward	_	$V_{GS} = 30 \text{ V}, V_{DS} = 0 \text{ V}$			100	
_	everse	I_{GSS}	$V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
ON CHARACTERISTICS		1	, 20 , 20 -	I			
Gate Threshold Voltage		V _{GS(TH)}	V _{DS} =V _{GS} , I _D =250µA	2.0		4.0	V
Drain-Source On-State Resistance		R _{DS(ON)}	V _{GS} =10V, I _D =9A		0.220	0.265	Ω
Forward Transconductance		9 FS	V _{DS} =40V, I _D =9A (Note 4)		25		S
DYNAMIC PARAMETERS		-					
Input Capacitance		C _{ISS}			2200	2860	pF
Output Capacitance		Coss	V _{DS} =25V,V _{GS} =0V,f=1.0MHz		330	430	pF
Reverse Transfer Capacitance		C _{RSS}			25	40	pF
SWITCHING PARAMETERS							
Total Gate Charge		Q_G	1/ 400/// 40// 1 40/		45	60	nC
Gate-Source Charge		Q_{GS}	V _{DS} =400V, V _{GS} =10V, I _D =18A (Note 4.5)		12.5		nC
Gate-Drain Charge		Q_{GD}	(Note 4,5)		19		nC
Turn-ON Delay Time	9				55	120	ns
Turn-ON Rise Time		t _R	V _{DD} =250V, I _D =18A,		165	340	ns
Turn-OFF Delay Time		t _{D(OFF)}	R _G =25Ω (Note 4,5)		95	200	ns
Turn-OFF Fall Time		t_{F}			90	190	ns
SOURCE- DRAIN DIODE RATINGS	S AND CH	ARACTERIS	TICS				
Maximum Body-Diode Continuous C	Current	I _S				18	Α
Maximum Body-Diode Pulsed Current		I _{SM}				72	Α
Drain-Source Diode Forward Voltage		V_{SD}	I _S =18A, V _{GS} =0V			1.4	V
Body Diode Reverse Recovery Time		t _{RR}	V _{GS} =0V, I _S =18A,		500		ns
Body Diode Reverse Recovery Char	rge	Q_{RR}	dI _F /dt=100A/μs (Note 4)		5.4		μC

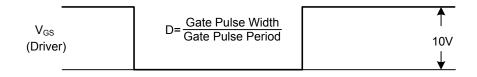
Notes: 1. Repetitive Rating: Pulse width limited by maximum junction temperature

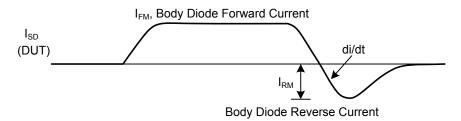
- 2. L=5.2mH, I_{AS} =18A, V_{DD} =50V, R_{G} =25 Ω , Starting T_{J} =25 $^{\circ}$ C
- 4. $I_{SD} \le 18A$, di/dt $\le 200A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25$ °C
- 4. Pulse Test : Pulse width≤300µs, Duty cycle≤2%
- 5. Essentially independent of operating temperature
- 6. Drain current limited by maximum junction temperature

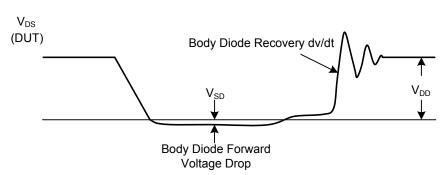
■ TEST CIRCUITS AND WAVEFORMS

Peak Diode Recovery dv/dt Test Circuit & Waveforms



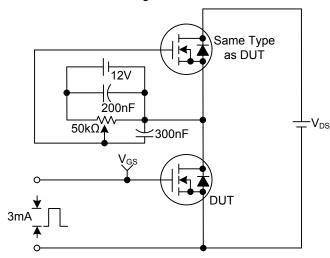




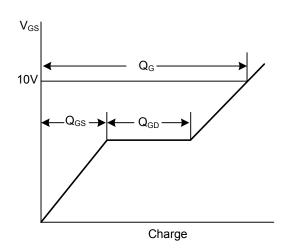


■ TEST CIRCUITS AND WAVEFORMS(Cont.)

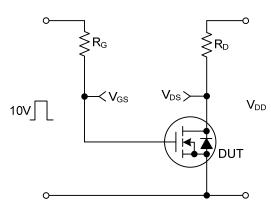
Gate Charge Test Circuit



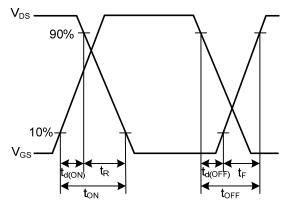
Gate Charge Waveforms



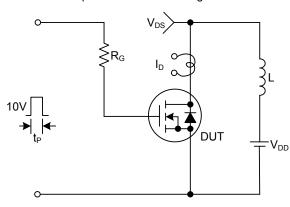
Resistive Switching Test Circuit



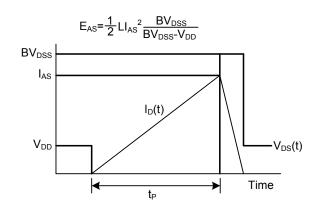
Resistive Switching Waveforms



Unclamped Inductive Switching Test Circuit



Unclamped Inductive Switching Waveforms



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